



IEEE Computer Society's Test Technology Technical Council (TTTC) &
IEEE Council on Electronic Design Automation (CEDA)

Certificate of Participation

This is to certify that

Gaku Ogihara, Takayuki Nakatani, Akemi Hatta, Keno Sato, Takashi Tshida, Toshiyuki Okamoto, Tamotsu Tchikawa, Anna Kuwana, Riko Aoki, Shogo Katayama, Jianshen Wei, Yujie Zhao, Jianlong Wang, Kazumi Hatayama and Haruo Kobayashi

has presented a paper titled

Summing Node Test Method: Simultaneous Multiple AC Characteristics Testing of Multiple Operational Amplifiers
at the 29th IEEE Asian Test Symposium hosted virtually from Malaysia on November 22~25, 2020.

Fawnizu Azmadi Hussin
General Co-Chair, ATS 2020

Michiko Inoue
General Co-Chair, ATS 2020

Chia Yee Ooi
Program Co-Chair, ATS 2020

Erik Larsson
Program Co-Chair, ATS 2020